

Herbert Hutter

List of Publications by Year in descending order

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143
papers

2,722
citations

201674

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148
all docs

148
docs citations

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times ranked

3460
citing authors

#	ARTICLE	IF	CITATIONS
1	Tensile Lattice Strain Accelerates Oxygen Surface Exchange and Diffusion in La _{1-x} Sr _x CoO ₃ Thin Films. ACS Nano, 2013, 7, 3276-3286.	14.6	211
2	Relationship between Cation Segregation and the Electrochemical Oxygen Reduction Kinetics of La _{0.6} Sr _{0.4} CoO ₃ Thin Film Electrodes. Journal of the Electrochemical Society, 2011, 158, B727-B734.	2.9	183
3	Cation diffusion in La _{0.6} Sr _{0.4} CoO ₃ below 800 °C and its relevance for Sr segregation. Physical Chemistry Chemical Physics, 2014, 16, 2715.	2.8	104
4	Fast oxygen exchange and diffusion kinetics of grain boundaries in Sr-doped LaMnO ₃ thin films. Physical Chemistry Chemical Physics, 2015, 17, 7659-7669.	2.8	92
5	A novel ToF-SIMS operation mode for sub 100nm lateral resolution: Application and performance. Applied Surface Science, 2014, 289, 407-416.	6.1	81
6	Dislocations Accelerate Oxygen Ion Diffusion in La _{0.8} Sr _{0.2} MnO ₃ Epitaxial Thin Films. ACS Nano, 2017, 11, 11475-11487.	14.6	80
7	The Effect of Acceptor and Donor Doping on Oxygen Vacancy Concentrations in Lead Zirconate Titanate (PZT). Materials, 2016, 9, 945.	2.9	66
8	Initial oxidation of silver surfaces by S ₂ and S ₄ ⁺ species. Corrosion Science, 2008, 50, 1112-1121.	6.6	64
9	Oxygen Vacancies in Fast Lithium-Ion Conducting Garnets. Chemistry of Materials, 2017, 29, 7189-7196.	6.7	63
10	Bulk and surface characterization of In ₂ O ₃ (001) single crystals. Physical Review B, 2012, 85, .	3.2	62
11	A novel ToF-SIMS operation mode for improved accuracy and lateral resolution of oxygen isotope measurements on oxides. Journal of Analytical Atomic Spectrometry, 2013, 28, 1080.	3.0	58
12	Influence of surface atomic structure demonstrated on oxygen incorporation mechanism at a model perovskite oxide. Nature Communications, 2018, 9, 3710.	12.8	54
13	Accelerated Ionic Motion in Amorphous Memristor Oxides for Nonvolatile Memories and Neuromorphic Computing. Advanced Functional Materials, 2019, 29, 1804782.	14.9	51
14	Investigation of the oxygen exchange mechanism on Pt yttria stabilized zirconia at intermediate temperatures: Surface path versus bulk path. Electrochimica Acta, 2011, 56, 9727-9740.	5.2	47
15	Three dimensional ultra trace analysis of materials. Mikrochimica Acta, 1992, 107, 137-148.	5.0	41
16	Characterisation of sputter deposited niobium and boron interlayer in the copper-diamond system. Surface and Coatings Technology, 2012, 208, 24-31.	4.8	40
17	Mutual Lewis Acid-Base Interactions of Cations and Anions in Ionic Liquids. Chemistry - A European Journal, 2013, 19, 288-293.	3.3	40
18	Low friction CrN/TiN multilayer coatings prepared by a hybrid high power impulse magnetron sputtering/DC magnetron sputtering deposition technique. Thin Solid Films, 2010, 518, 5553-5557.	1.8	39

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19	Visualization of oxygen reduction sites at Pt electrodes on YSZ by means of ^{18}O tracer incorporation: the width of the electrochemically active zone. <i>Physical Chemistry Chemical Physics</i> , 2010, 12, 12734.	2.8	38
20	CO addition in low-pressure chemical vapour deposition of medium-temperature $\text{Ti}_x\text{N}_{1-x}$ based hard coatings. <i>Surface and Coatings Technology</i> , 2011, 206, 1691-1697.	4.8	37
21	Designing properties of $(\text{Na}_{1/2}\text{Bi}_x)\text{TiO}_3$ -based materials through A-site non-stoichiometry. <i>Journal of Materials Chemistry C</i> , 2018, 6, 738-744.	5.5	37
22	Digital holographic reflectometry. <i>Optics Express</i> , 2010, 18, 3719.	3.4	36
23	The relevance of interfaces for oxide ion transport in yttria stabilized zirconia (YSZ) thin films. <i>Physical Chemistry Chemical Physics</i> , 2013, 15, 1097-1107.	2.8	36
24	Solar wind sputtering of wollastonite as a lunar analogue material – Comparisons between experiments and simulations. <i>Icarus</i> , 2018, 314, 98-105.	2.5	30
25	Thin film cathodes in SOFC research: How to identify oxygen reduction pathways?. <i>Journal of Materials Research</i> , 2013, 28, 2085-2105.	2.6	28
26	Electrochemical properties of $\text{La}_{0.6}\text{Sr}_{0.4}\text{CoO}_3$ thin films investigated by complementary impedance spectroscopy and isotope exchange depth profiling. <i>Solid State Ionics</i> , 2014, 256, 38-44.	2.7	28
27	Temperature gradients in microelectrode measurements: Relevance and solutions for studies of SOFC electrode materials. <i>Solid State Ionics</i> , 2014, 268, 82-93.	2.7	28
28	Oxygen vacancy redistribution in $\text{PbZr}_x\text{Ti}_{1-x}\text{O}_3$ (PZT) under the influence of an electric field. <i>Solid State Ionics</i> , 2014, 262, 625-629.	2.7	28
29	Investigations on the effects of plasma-assisted pre-treatment for plasma-assisted chemical vapour deposition TiN coatings on tool steel. <i>Thin Solid Films</i> , 2004, 461, 277-281.	1.8	27
30	Comparison of WTi and WTi(N) as diffusion barriers for Al and Cu metallization on Si with respect to thermal stability and diffusion behavior of Ti. <i>Microelectronics Reliability</i> , 2014, 54, 2487-2493.	1.7	26
31	Measurement of ^{18}O tracer diffusion coefficients in thin yttria stabilized zirconia films. <i>Solid State Ionics</i> , 2011, 184, 23-26.	2.7	25
32	Water-Induced Decoupling of Tracer and Electrochemical Oxygen Exchange Kinetics on Mixed Conducting Electrodes. <i>Journal of Physical Chemistry Letters</i> , 2016, 7, 2826-2831.	4.6	24
33	Microstructural characterisation of five simulated archaeological copper alloys using light microscopy, scanning electron microscopy, energy dispersive X-ray microanalysis and secondary ion mass spectrometry. <i>Analytica Chimica Acta</i> , 2001, 440, 189-198.	5.4	23
34	The wetting behaviour of silver on carbon, pure and carburized nickel, cobalt and molybdenum substrates. <i>Applied Surface Science</i> , 2010, 256, 4697-4701.	6.1	23
35	Oxide Ion Transport in Donor-Doped $\text{Pb}(\text{Zr}_x\text{Ti}_{1-x})\text{O}_3$: The Role of Grain Boundaries. <i>Journal of the American Ceramic Society</i> , 2011, 94, 1173-1181.	3.8	22
36	Pt-assisted oxidation of (100)-Ge/high-k interfaces and improvement of their electrical quality. <i>Applied Physics Letters</i> , 2010, 97, .	3.3	21

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37	Carbon doped $\hat{\pm}$ -Al ₂ O ₃ coatings grown by chemical vapor deposition. Surface and Coatings Technology, 2012, 206, 4771-4777.	4.8	21
38	The Sulphur Poisoning Behaviour of Gadolinia Doped Ceria Model Systems in Reducing Atmospheres. Materials, 2016, 9, 649.	2.9	21
39	Influence of oxygen impurities on growth morphology, structure and mechanical properties of Ti $\hat{\pm}$ Al $\hat{\pm}$ N thin films. Thin Solid Films, 2016, 603, 39-49.	1.8	21
40	Oxide Ion Transport in Donor $\hat{\pm}$ Doped $\langle \text{scp} \rangle \langle \text{scp} \rangle \text{Pb} \langle / \text{scp} \rangle \langle / \text{scp} \rangle (\langle \text{scp} \rangle \langle \text{scp} \rangle \text{Zr} \langle / \text{scp} \rangle \langle / \text{scp} \rangle \langle \text{sub} \rangle \langle \text{i} \rangle \langle \text{x} \rangle \langle / \text{i} \rangle \langle / \text{sub} \rangle \langle \text{scp} \rangle \langle \text{scp} \rangle \text{Ti} \langle / \text{scp} \rangle \langle / \text{scp} \rangle \langle \text{sub} \rangle \langle \text{l} \rangle \langle \text{a} \rangle \langle \text{s} \rangle \langle / \text{sub} \rangle \langle \text{scp} \rangle \langle \text{scp} \rangle \text{Near} \hat{\pm}$ Surface Diffusion Properties. Journal of the American Ceramic Society, 2012, 95, 1692-1700.	3.8	18
41	Trends in surface and interface analysis. Fresenius' Journal of Analytical Chemistry, 1993, 346, 594-603.	1.5	17
42	WC $\hat{\pm}$ Co substrate surface pretreatments with aluminum compounds prior to polycrystalline CVD diamond deposition. International Journal of Refractory Metals and Hard Materials, 1999, 17, 445-452.	3.8	16
43	Topochemical characterization of materials using 3D-SIMS. Fresenius' Journal of Analytical Chemistry, 1993, 346, 66-68.	1.5	15
44	Influence of increasing zinc contents in brass in the early stages of corrosion investigated by in-situ TM-AFM and SIMS. Analytical and Bioanalytical Chemistry, 2002, 374, 338-343.	3.7	15
45	Adhesion promotion of Cu on C by Cr intermediate layers investigated by the SIMS method. Analytical and Bioanalytical Chemistry, 2002, 374, 602-607.	3.7	15
46	ToF-SIMS measurements with topographic information in combined images. Analytical and Bioanalytical Chemistry, 2013, 405, 7161-7167.	3.7	15
47	ToF-SIMS analysis for leaching studies of potash $\hat{\pm}$ lime $\hat{\pm}$ silica glass. Applied Surface Science, 2013, 282, 195-201.	6.1	15
48	Sol $\hat{\pm}$ gel silica coating for potash $\hat{\pm}$ lime $\hat{\pm}$ silica stained glass: Applicability and protective effect. Journal of Non-Crystalline Solids, 2014, 390, 45-50.	3.1	15
49	Metal assisted photochemical etching of 4H silicon carbide. Journal Physics D: Applied Physics, 2017, 50, 435301.	2.8	15
50	TOF-SIMS investigations on weathered silver surfaces. Analytical and Bioanalytical Chemistry, 2008, 390, 1543-1549.	3.7	14
51	On the temperature dependence of Na migration in thin SiO ₂ films during ToF-SIMS O ₂ ⁺ depth profiling. Applied Surface Science, 2010, 257, 25-32.	6.1	14
52	Oxidation and diffusion study on AlCrVN hard coatings using oxygen isotopes ¹⁶ O and ¹⁸ O. Thin Solid Films, 2011, 519, 3974-3981.	1.8	14
53	Potassium self-diffusion in a K-rich single-crystal alkali feldspar. Physics and Chemistry of Minerals, 2017, 44, 345-351.	0.8	14
54	Large O ₂ Cluster Ions as Sputter Beam for ToF-SIMS Depth Profiling of Alkali Metals in Thin SiO ₂ Films. Analytical Chemistry, 2017, 89, 2377-2382.	6.5	14

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55	Range evaluation in SIMS depth profiles of Er-implantations in silicon. <i>Applied Surface Science</i> , 2005, 252, 271-277.	6.1	13
56	Apparent Oxygen Uphill Diffusion in La _{0.8} Sr _{0.2} MnO ₃ Thin Films upon Cathodic Polarization. <i>ChemElectroChem</i> , 2015, 2, 1487-1494.	3.4	13
57	Potash-lime-silica glass: protection from weathering. <i>Heritage Science</i> , 2015, 3, .	2.3	13
58	Cu gettering in ion implanted and annealed silicon in regions before and beyond the mean projected ion range. <i>Journal of Applied Physics</i> , 2003, 94, 3834-3839.	2.5	12
59	Investigations of corrosion phenomena on gold coins with SIMS. <i>Applied Surface Science</i> , 2005, 252, 133-138.	6.1	12
60	Characterization of the mechanical and thermal interface of copper films on carbon substrates modified by boron based interlayers. <i>Surface and Coatings Technology</i> , 2011, 205, 3729-3735.	4.8	12
61	Interplay of Grain Size Dependent Electronic and Ionic Conductivity in Electrochemical Polarization Studies on Sr-Doped LaMnO ₃ (LSM) Thin Film Cathodes. <i>Journal of the Electrochemical Society</i> , 2018, 165, F702-F709.	2.9	12
62	3D-SIMS analysis of ultra high purity molybdenum and tungsten: a characterisation of different manufacturing techniques and products. <i>Fresenius' Journal of Analytical Chemistry</i> , 1995, 353, 524-532.	1.5	11
63	Fusion of 2-D SIMS Images Using the Wavelet Transform. <i>Mikrochimica Acta</i> , 2000, 133, 273-278.	5.0	11
64	Oxygen Ion Conduction in Bulk and Grain Boundaries of Nominally Donor-Doped Lead Zirconate Titanate (<sc>PZT</sc>): A Combined Impedance and Tracer Diffusion Study. <i>Journal of the American Ceramic Society</i> , 2015, 98, 3259-3269.	3.8	11
65	The wavelet transform: A new preprocessing method for peak recognition of infrared spectra. <i>Mikrochimica Acta</i> , 1998, 128, 241-250.	5.0	10
66	Characterisation of Cr intermediate layers in Cu-C system with SIMS method. <i>Applied Surface Science</i> , 2001, 179, 275-280.	6.1	10
67	Comparative study of LNO, LSCO and LSMO as electrode layers for microelectronic capacitors by dynamic SIMS. <i>Surface and Coatings Technology</i> , 2002, 150, 119-124.	4.8	10
68	SIMS and TM-AFM Studies on Weathered Cu, Zn, and Brass (CuZn10, CuZn30) Surfaces. <i>Instrumentation Science and Technology</i> , 2003, 21, 49-62.	0.8	10
69	Analysis of antioxidants in insulation cladding of copper wire: a comparison of different mass spectrometric techniques (ESI-IT, MALDI-TOF and RTOF-SIMS). <i>Journal of Mass Spectrometry</i> , 2009, 44, 1724-1732.	1.6	10
70	The Chemical Capacitance as a Fingerprint of Defect Chemistry in Mixed Conducting Oxides. <i>Acta Chimica Slovenica</i> , 2016, 63, 509-518.	0.6	10
71	Maximum entropy deconvolution of AFM and STM images. <i>Fresenius' Journal of Analytical Chemistry</i> , 1995, 351, 143-147.	1.5	9
72	Characterisation of molybdenum intermediate layers in Cu-C system with SIMS method. <i>Applied Surface Science</i> , 2005, 252, 266-270.	6.1	9

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73	Investigation of polymer thin films by use of Bi-cluster-ion-supported time of flight secondary ion mass spectrometry. <i>Analytical and Bioanalytical Chemistry</i> , 2009, 393, 1889-1898.	3.7	9
74	Reduction of the PtGe/Ge Electron Schottky-Barrier Height by Rapid Thermal Diffusion of Phosphorous Dopants. <i>Journal of the Electrochemical Society</i> , 2010, 157, H815.	2.9	9
75	Experimental Design for Voltage Driven Tracer Incorporation and Diffusion Studies on Oxide Thin Film Electrodes. <i>Journal of the Electrochemical Society</i> , 2017, 164, F809-F814.	2.9	9
76	Characterization of Two-Component Metal Coatings (Al/Sn) with SIMS. <i>Mikrochimica Acta</i> , 2000, 133, 267-271.	5.0	8
77	Characterization of the 3D-distribution of the components in Al-alloyed high speed steels with SIMS. <i>Applied Surface Science</i> , 2001, 179, 240-244.	6.1	8
78	SIMS Investigations on the Distribution of Trace Elements in Modified Aluminium-Silicon-Magnesium Alloys. <i>Mikrochimica Acta</i> , 2003, 141, 23-27.	5.0	8
79	Characterization of the distribution of the sintering activator boron in powder metallurgical steels with SIMS. <i>Analytical and Bioanalytical Chemistry</i> , 2004, 379, 605-9.	3.7	8
80	Phosphorus as sintering activator in powder metallurgical steels: characterization of the distribution and its technological impact. <i>Analytical and Bioanalytical Chemistry</i> , 2004, 379, 610-8.	3.7	8
81	Influences of the nitrogen content on the morphological, chemical and optical properties of pulsed laser deposited silicon nitride thin films. <i>Surface and Coatings Technology</i> , 2005, 192, 225-230.	4.8	8
82	TOF-SIMS depth profiling and element mapping on oxidized AlCrVN hard coatings. <i>Analytical and Bioanalytical Chemistry</i> , 2009, 393, 1857-1861.	3.7	8
83	Strain-induced structure and oxygen transport interactions in epitaxial La _{0.6} Sr _{0.4} CoO ₃ thin films. <i>Communications Materials</i> , 2020, 1, .	6.9	8
84	Charge distribution in light emitting electrochemical cells. <i>Synthetic Metals</i> , 1999, 102, 1022-1023.	3.9	7
85	SIMS: a capable method for BCN quantification. <i>Applied Surface Science</i> , 2000, 167, 79-88.	6.1	7
86	SIMS Characterisation of Aluminum-Alloyed Hot Isostatic Pressed Steel. <i>Mikrochimica Acta</i> , 2000, 133, 261-266.	5.0	7
87	Investigation of ionic liquids under Bi ⁺ and Bi ⁺ cluster ions bombardment by ToF-SIMS. <i>Journal of Mass Spectrometry</i> , 2010, 45, 1104-1110.	1.6	7
88	Stacked Layers of Different Porosity in 4H SiC Substrates Applying a Photoelectrochemical Approach. <i>Journal of the Electrochemical Society</i> , 2017, 164, E337-E347.	2.9	7
89	Maximum entropy deconvolution of secondary ion mass spectra with a measured response. <i>Fresenius' Journal of Analytical Chemistry</i> , 1994, 349, 186-190.	1.5	6
90	Classification of secondary ion mass spectrometry (SIMS) micrographs to characterize chemical phases. <i>Mikrochimica Acta</i> , 1995, 119, 1-12.	5.0	6

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91	SAM investigations of temperature programmed surface segregation of impurities in γ -iron. Fresenius' Journal of Analytical Chemistry, 1995, 353, 762-765.	1.5	6
92	Impact of Germanium Surface Conditioning and ALD-growth Temperature on Al ₂ O ₃ /ZrO ₂ High-k Dielectric Stacks. Journal of the Electrochemical Society, 2009, 156, G168.	2.9	6
93	The effect of bias-temperature stress on Na ⁺ incorporation into thin insulating films. Analytical and Bioanalytical Chemistry, 2011, 400, 649-657.	3.7	6
94	Mapping electrochemically driven gas exchange of mixed conducting SrTi _{0.7} Fe _{0.3} O ₃ and Ce _{0.8} Gd _{0.2} O _{1.9} thin films by ¹⁸ O tracer incorporation under reducing atmosphere. Solid State Ionics, 2015, 273, 25-29.	2.7	6
95	The Effect of Mn Co-doping on the Electrochemical Properties of Gd _{0.2} Ce _{0.8} O _{1.9} /Pt Model-composite Electrodes. ECS Transactions, 2015, 68, 1509-1516.	0.5	6
96	Local Ions Distribution Inhomogeneities in Polymer Based Light Emitting Cells. Mikrochimica Acta, 2000, 135, 131-137.	5.0	5
97	INVESTIGATIONS ON CODEPOSITED ALUMINUM-TIN SYSTEMS WITH SIMS. Instrumentation Science and Technology, 2001, 19, 91-98.	0.8	5
98	Novel monodisperse PEG-grafted polystyrene resins: synthesis and application in gel-phase ¹³ C NMR spectroscopy. Tetrahedron Letters, 2008, 49, 7103-7105.	1.4	5
99	Lanthanum-Zirconate and Lanthanum-Aluminate Based High- ϵ Dielectric Stacks on Silicon Substrates. Journal of the Electrochemical Society, 2009, 156, G53.	2.9	5
100	Suppression of de-wetting of copper coatings on carbon substrates by metal (Cr, Mo, Ti) doped boron interlayers. Vacuum, 2009, 84, 202-204.	3.5	5
101	Correction of topographic artefacts of ToF-SIMS element distributions. Surface and Interface Analysis, 2013, 45, 457-460.	1.8	5
102	Automatic matching of SAM, SIMS and EPMA images. Fresenius' Journal of Analytical Chemistry, 1994, 349, 197-199.	1.5	4
103	Investigation of the formation and properties of protective oxide layers on high purity chromium with SIMS imaging techniques. Mikrochimica Acta, 1997, 125, 69-72.	5.0	4
104	Compression of Secondary Ion Microscopy Image Sets Using a Three-dimensional Wavelet Transformation. Microscopy and Microanalysis, 2000, 6, 68-75.	0.4	4
105	2D- and 3D SIMS investigations on hot-pressed steel powder HS 6-5-3-8. Analytical and Bioanalytical Chemistry, 2002, 374, 597-601.	3.7	4
106	SIMS investigation of CrN sputtercoatings. Analytical and Bioanalytical Chemistry, 2002, 374, 592-596.	3.7	4
107	AES and SIMS analysis of non-metallic inclusions in a low-carbon Chromium-steel. Analytical and Bioanalytical Chemistry, 2003, 376, 255-259.	3.7	4
108	Quantitative SIMS depth profiling of diffusion barrier gate-oxynitride structures in TFT-LCDs. Analytical and Bioanalytical Chemistry, 2004, 379, 599-604.	3.7	4

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109	Low energy RBS and SIMS analysis of the SiGe quantum well. Applied Surface Science, 2005, 252, 123-126.	6.1	4
110	SIMS investigation of gettering centres produced by phosphorus MeV ion implantation. Applied Surface Science, 2005, 252, 278-281.	6.1	4
111	2D and 3D SIMS investigations on sintered steels. Applied Surface Science, 2005, 252, 282-285.	6.1	4
112	Quantitative analysis of the Ge concentration in a SiGe quantum well: comparison of low-energy RBS and SIMS measurements. Analytical and Bioanalytical Chemistry, 2005, 384, 525-530.	3.7	4
113	Study of metabolism and identification of productive regions in filamentous fungi via spatially resolved time-of-flight secondary ion mass spectrometry. Analytical and Bioanalytical Chemistry, 2020, 412, 2081-2088.	3.7	4
114	Characterization of oxygen precipitates in Czochralski silicon by imaging SIMS. Mikrochimica Acta, 1992, 107, 149-160.	5.0	3
115	Imaging SIMS for the investigation of substrate surfaces for CVD diamond deposition. Fresenius' Journal of Analytical Chemistry, 1995, 352, 313-317.	1.5	3
116	Visualization of n-dimensional analytical data on personal computers1The images in this article can be viewed in colour at http://www.elsevier.nl/locate/trac . Click on the Supplementary material link.1. TrAC - Trends in Analytical Chemistry, 1998, 17, 120-128.	11.4	3
117	Characterization of the Element Distribution Within TiN Coatings with SIMS. Mikrochimica Acta, 2000, 135, 105-111.	5.0	3
118	Quantitative Sputter Depth Profiling of Silicon- and Aluminium Oxynitride Films. Mikrochimica Acta, 2000, 133, 75-87.	5.0	3
119	Investigations on the Thermal Cycling Stability of SiFeCr Coated NbtZr. Mikrochimica Acta, 2000, 133, 89-93.	5.0	3
120	Chemical solution-deposited PbZr _{0.53} Ti _{0.47} O ₃ on La _{0.5} Sr _{0.5} CoO ₃ . SIMS investigation of the effect of different precursor additives on the layer structure. Analytical and Bioanalytical Chemistry, 2002, 374, 608-613.	3.7	3
121	Characterisation of the interface of sputter-deposited copper coatings on nitrogen plasma-treated carbon substrates. Analytical and Bioanalytical Chemistry, 2004, 380, 838-842.	3.7	3
122	Investigation of gettering effects in CZ-type silicon with SIMS. Analytical and Bioanalytical Chemistry, 2005, 381, 1526-1531.	3.7	3
123	Oxygen diffusion in grain boundaries: a ToF-SIMS investigation on hot-rolled steel sheets. Analytical and Bioanalytical Chemistry, 2011, 400, 659-663.	3.7	3
124	Oxygen transport in electroceramics investigated by electrochemical ¹⁸ O/ ¹⁶ O isotope exchange and ToF-SIMS. Surface and Interface Analysis, 2013, 45, 486-489.	1.8	3
125	Atmospheric Pressure Matrix-Assisted Laser Desorption/Ionization Mass Spectrometry of Friction Modifier Additives Analyzed Directly from Base Oil Solutions. European Journal of Mass Spectrometry, 2014, 20, 299-305.	1.0	3
126	Modified-Atmospheric Pressure-Matrix Assisted Laser Desorption/Ionization Identification of Friction Modifier Additives Oleamide and Ethoxylated Tallow Amines on Varied Metal Target Materials and Tribologically Stressed Steel Surfaces. Analytical Chemistry, 2015, 87, 11375-11382.	6.5	3

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127	Investigation of Electric Field Induced Ion Migration in Semiconductor Encapsulation Materials without the Interference of Electron Conductivity. ECS Journal of Solid State Science and Technology, 2016, 5, N72-N76.	1.8	3
128	Quantitative characterization of oxygen precipitates in CZ-silicon with secondary ion mass spectrometry. Fresenius' Journal of Analytical Chemistry, 1991, 341, 112-115.	1.5	2
129	Channelplate Illumination Correction for Secondary Ion Mass Spectroscopy Images by Solving Apparatus Elasticity Equations. Microscopy and Microanalysis, 1999, 5, 407-412.	0.4	2
130	Application of SIMS in Re-Technology Studies: Characterization of Trace-Element Distributions and Quantitative of Carbon-Determination. Mikrochimica Acta, 2000, 133, 253-259.	5.0	2
131	TOF-SIMS investigations on thermally treated copper-molybdenum films on a carbon substrate. Analytical and Bioanalytical Chemistry, 2008, 390, 1537-1541.	3.7	2
132	Investigation of the Oxygen Exchange Reaction on Pt/YSZ: The Relation between Three Phase Boundaries and Electrode Performance. ECS Transactions, 2009, 25, 2783-2792.	0.5	2
133	Investigation of n -butylmethylimidazolium bis(trifluoromethylsulfonyl)imide under x cluster ion bombardment. Surface and Interface Analysis, 2010, 42, 1025-1029.	1.8	2
134	Surface Cation Segregation and its Effect on the Oxygen Reduction Reaction on Mixed Conducting Electrodes Investigated by ToF-SIMS and ICP-OES. ECS Transactions, 2011, 35, 1975-1983.	0.5	2
135	Monitoring Active and Resistive Zones of SOFC Cathodes by Voltage Driven Tracer Incorporation. ECS Transactions, 2011, 35, 2217-2226.	0.5	2
136	Near-surface transport properties of donor doped $Pb(Zr_{1-x}Ti_x)O_3$ (PZT) in an external electric field. Solid State Ionics, 2012, 225, 727-731.	2.7	2
137	(Invited) Ion Transfer and Ion Transport in Thin Oxide Films Investigated by Complementary Tracer Diffusion and Impedance Spectroscopy Measurements. ECS Transactions, 2012, 45, 203-212.	0.5	2
138	Rhodium Germanide Schottky Barrier Contacts. ECS Journal of Solid State Science and Technology, 2015, 4, P387-P392.	1.8	2
139	Differences between Li, Na, and K migration in thin SiO_2 films during ToF-SIMS O_2^+ depth profiling. Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics, 2018, 36, .	1.2	2
140	Clarification by TEM and SIMS of abnormal Ti depth distribution in chemical solution-deposited $SrTiO_3/La_{0.5}Sr_{0.5}CoO_3$. Fresenius' Journal of Analytical Chemistry, 2001, 371, 54-57.	1.5	1
141	Insertion behavior of sodium and potassium ions into thin CVD SiO_x layers by means of a triangular voltage sweep method. Surface and Interface Analysis, 2016, 48, 636-649.	1.8	1
142	Acquisition of artifact free alkali metal distributions in SiO_2 by ToF-SIMS Cs ⁺ depth profiling at low temperatures. Surface and Interface Analysis, 2021, 53, 675-680.	1.8	1
143	Study on the Ion Migration of Silver Ions from Aqueous Solution in Epoxy-Based Molding Compounds by TOF-SIMS Measurements. ECS Journal of Solid State Science and Technology, 2022, 11, 024006.	1.8	0